


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,446	LEE ET AL.	
	Examiner	Art Unit	
	Matthew G. Kayrish	2653	

SEARCHED			
Class	Subclass	Date	Examiner
720	602	12/19/2005	MK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-PGPUB, USPAT, USOCR) (See Attached Search History)	12/19/2005	MK
EAST (EPO, JPO, DERWENT, IBM_TDB) (See Attached Search History)	12/19/2005	MK
EAST (US-PGPUB, USPAT, USOCR) (See Attached Search History)	12/23/2005	MK